

### October 21, 2004

FN4022.13

### 100V/2A Peak, Low Cost, High Frequency Half Bridge Driver

The HIP2100 is a high frequency, 100V Half Bridge N-Channel power MOSFET driver IC. The low-side and high-side gate drivers are independently controlled and matched to 8ns. This gives the user maximum flexibility in dead-time selection and driver protocol. Undervoltage protection on both the low-side and high-side supplies force the outputs low. An on-chip diode eliminates the discrete diode required with other driver ICs. A new level-shifter topology yields the low-power benefits of pulsed operation with the safety of DC operation. Unlike some competitors, the high-side output returns to its correct state after a momentary undervoltage of the high-side supply.

# **Ordering Information**

intercil

PART #	TEMP. RANGE (°C)	PACKAGE	PKG. DWG. #
HIP2100IB	-40 to 125	8 Ld SOIC	M8.15
HIP2100IBZ (Note 1)	-40 to 125	8 Ld SOIC (Pb-free)	M8.15
HIP2100EIB	-40 to 125	8 Ld EPSOIC	M8.15C
HIP2100EIBZ (Note 1)	-40 to 125	8 Ld EPSOIC (Pb-free)	M8.15C
HIP2100IR	-40 to 125	16 Ld 5x5 QFN	L16.5x5
HIP2100IRZ (Note 1)	-40 to 125	16 Ld 5x5 QFN (Pb-free)	L16.5x5
HIP2100IR4	-40 to 125	12 Ld 4x4 DFN	L12.4x4A
HIP2100IR4Z (Note 1)	-40 to 125	12 Ld 4x4 DFN (Pb-free)	L12.4x4A

NOTES:

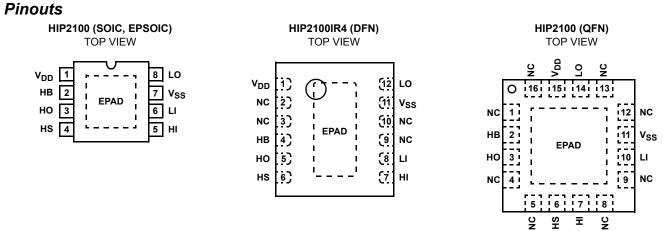
- Intersil Pb-free products employ special Pb-free material sets; molding compounds/die attach materials and 100% matte tin plate termination finish, which are RoHS compliant and compatible with both SnPb and Pb-free soldering operations. Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020C.
- 2. Add "T" suffix for Tape and Reel packing option.

### Features

- Drives N-Channel MOSFET Half Bridge
- SOIC, EPSOIC, QFN and DFN Package Options
- SOIC, EPSOIC and DFN Packages Compliant with 100V Conductor Spacing Guidelines of IPC-2221
- Pb-Free Product Available (RoHS Compliant)
- Bootstrap Supply Max Voltage to 114VDC
- On-Chip 1Ω Bootstrap Diode
- Fast Propagation Times for Multi-MHz Circuits
- Drives 1000pF Load with Rise and Fall Times Typ. 10ns
- CMOS Input Thresholds for Improved Noise Immunity
- Independent Inputs for Non-Half Bridge Topologies
- No Start-Up Problems
- Outputs Unaffected by Supply Glitches, HS Ringing Below Ground, or HS Slewing at High dv/dt
- Low Power Consumption
- Wide Supply Range
- Supply Undervoltage Protection
- 3Ω Driver Output Resistance
- QFN/DFN Package:
  - Compliant to JEDEC PUB95 MO-220 QFN - Quad Flat No Leads - Package Outline
  - Near Chip Scale Package footprint, which improves PCB efficiency and has a thinner profile

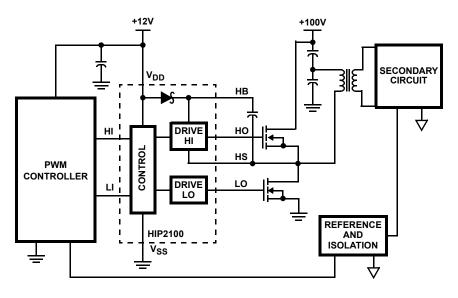
# Applications

- Telecom Half Bridge Power Supplies
- Avionics DC-DC Converters
- Two-Switch Forward Converters
- Active Clamp Forward Converters

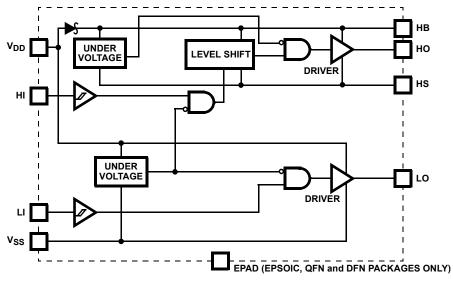


NOTE: EPAD = Exposed PAD.

### Application Block Diagram



### Functional Block Diagram



\*EPAD = Exposed Pad. The EPAD is electrically isolated from all other pins. For best thermal performance connect the EPAD to the PCB power ground plane.

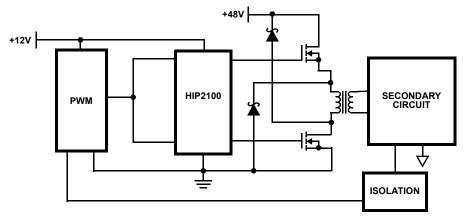


FIGURE 1. TWO-SWITCH FORWARD CONVERTER

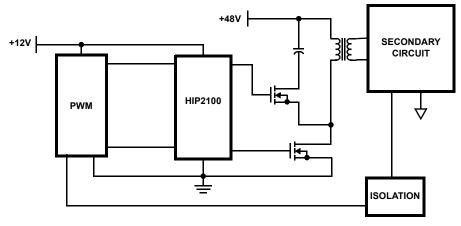


FIGURE 2. FORWARD CONVERTER WITH AN ACTIVE CLAMP

### **Absolute Maximum Ratings**

Supply Voltage, V <sub>DD</sub> , V <sub>HB</sub> -V <sub>HS</sub> (Notes 3, 4)0.3V to 18V
LI and HI Voltages (Note 4)0.3V to V <sub>DD</sub> +0.3V
Voltage on LO (Note 4)
Voltage on HO (Note 4) $V_{HS}$ -0.3V to $V_{HB}$ +0.3V
Voltage on HS (Continuous) (Note 4)1V to 110V
Voltage on HB (Note 4) +118V
Average Current in V <sub>DD</sub> to HB diode
ESD Classification

### **Maximum Recommended Operating Conditions**

Supply Voltage, V <sub>DD</sub>	+9V to 14.0VDC
Voltage on HS	
Voltage on HS(Repe	etitive Transient) -5V to 105V
Voltage on HB V <sub>HS</sub> +8V to V <sub>HS</sub> +14.0	V and V <sub>DD</sub> -1V to V <sub>DD</sub> +100V
HS Slew Rate	<50V/ns

### **Thermal Information**

Thermal Resistance (Typical)	θ <sub>JA</sub> (°C/W)	θ <sub>JC</sub> (°C/W)
SOIC (Note 5)	95	N/A
EPSOIC (Note 6)	40	3.0
QFN (Note 6)	37	6.5
DFN (Note 6)	40	3.0
Max Power Dissipation at 25°C in Free Air (	SOIC, Note 5)	) 1.3W
Max Power Dissipation at 25°C in Free Air (	EPSOIC, Note	e 6) 3.1W
Max Power Dissipation at 25°C in Free Air (	QFN, Note 6)	3.3W
Storage Temperature Range	6	5°C to 150°C
Junction Temperature Range	5!	5°C to 150°C
Lead Temperature (Soldering 10s - SOIC	Lead Tips On	ly) 300°C
For Recommended soldering conditions s	ee Tech Brief	TB389.

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the recommended operating conditions of this specification is not implied.

NOTES:

- 3. The HIP2100 is capable of derated operation at supply voltages exceeding 14V. Figure 16 shows the high-side voltage derating curve for this mode of operation.
- 4. All voltages referenced to  $\mathsf{V}_{SS}$  unless otherwise specified.
- 5.  $\theta_{JA}$  is measured with the component mounted on a high effective thermal conductivity test board in free air. See Tech Brief TB379 for details.
- θ<sub>JA</sub> is measured in free air with the component mounted on a high effective thermal conductivity test board with "direct attach" features. θ<sub>JC</sub>, the "case temp" is measured at the center of the exposed metal pad on the package underside. See Tech Brief TB379.

### Electrical Specifications V<sub>DD</sub> = V<sub>HB</sub> = 12V, V<sub>SS</sub> = V<sub>HS</sub> = 0V, No Load on LO or HO, Unless Otherwise Specified

			1	T <sub>J</sub> = 25°C		T <sub>J</sub> = -40°C TO 125°C		
PARAMETERS	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	MIN	MAX	UNITS
SUPPLY CURRENTS								
V <sub>DD</sub> Quiescent Current	I <sub>DD</sub>	LI = HI = 0V	-	0.1	0.15	-	0.2	mA
V <sub>DD</sub> Operating Current	I <sub>DDO</sub>	f = 500kHz	-	1.5	2.5	-	3	mA
Total HB Quiescent Current	I <sub>HB</sub>	LI = HI = 0V	-	0.1	0.15	-	0.2	mA
Total HB Operating Current	I <sub>HBO</sub>	f = 500kHz	-	1.5	2.5	-	3	mA
HB to V <sub>SS</sub> Current, Quiescent	I <sub>HBS</sub>	V <sub>HS</sub> = V <sub>HB</sub> = 114V	-	0.05	1	-	10	μA
HB to V <sub>SS</sub> Current, Operating	I <sub>HBSO</sub>	f = 500kHz	-	0.7	-	-	-	mA
INPUT PINS			i					
Low Level Input Voltage Threshold	V <sub>IL</sub>		4	5.4	-	3	-	V
High Level Input Voltage Threshold	V <sub>IH</sub>		-	5.8	7	-	8	V
Input Voltage Hysteresis	V <sub>IHYS</sub>		-	0.4	-	-	-	V
Input Pulldown Resistance	RI		-	200	-	100	500	kΩ
UNDERVOLTAGE PROTECTION								
V <sub>DD</sub> Rising Threshold	V <sub>DDR</sub>		7	7.3	7.8	6.5	8	V
V <sub>DD</sub> Threshold Hysteresis	V <sub>DDH</sub>		-	0.5	-	-	-	V
HB Rising Threshold	V <sub>HBR</sub>		6.5	6.9	7.5	6	8	V
HB Threshold Hysteresis	V <sub>HBH</sub>		-	0.4	-	-	-	V

<b>Electrical Specifications</b>	V <sub>DD</sub> = V <sub>HB</sub> = 12V, V <sub>SS</sub> = V <sub>HS</sub> = 0V, No Load on LO or HO, Unless Otherwise Specified (Continued)
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	T <sub>J</sub> = 25°C			с	T <sub>J</sub> = -40°C TO 125°C			
PARAMETERS	SYMBOL	TEST CONDITIONS	MIN	ТҮР	MAX	MIN	MAX	UNITS
BOOT STRAP DIODE								
Low-Current Forward Voltage	V <sub>DL</sub>	I <sub>VDD-HB</sub> = 100μA	-	0.45	0.55	-	0.7	V
High-Current Forward Voltage	V <sub>DH</sub>	I <sub>VDD-HB</sub> = 100mA	-	0.7	0.8	-	1	V
Dynamic Resistance	R <sub>D</sub>	I <sub>VDD-HB</sub> = 100mA	-	0.8	1	-	1.5	Ω
LO GATE DRIVER								
Low Level Output Voltage	V <sub>OLL</sub>	I <sub>LO</sub> = 100mA	-	0.25	0.3	-	0.4	V
High Level Output Voltage	V <sub>OHL</sub>	$I_{LO}$ = -100mA, $V_{OHL}$ = $V_{DD}$ - $V_{LO}$	-	0.25	0.3	-	0.4	V
Peak Pullup Current	IOHL	V <sub>LO</sub> = 0V	-	2	-	-	-	А
Peak Pulldown Current	IOLL	V <sub>LO</sub> = 12V	-	2	-	-	-	А
HO GATE DRIVER					r			
Low Level Output Voltage	V <sub>OLH</sub>	I <sub>HO</sub> = 100mA	-	0.25	0.3	-	0.4	V
High Level Output Voltage	V <sub>OHH</sub>	I <sub>HO</sub> = -100mA, V <sub>OHH</sub> = V <sub>HB</sub> -V <sub>HO</sub>	-	0.25	0.3	-	0.4	V
Peak Pullup Current	Іонн	V <sub>HO</sub> = 0V	-	2	-	-	-	А
Peak Pulldown Current	I <sub>OLH</sub>	V <sub>HO</sub> = 12V	-	2	-	-	-	А

**Switching Specifications**  $V_{DD} = V_{HB} = 12V$ ,  $V_{SS} = V_{HS} = 0V$ , No Load on LO or HO, Unless Otherwise Specified

		TEST	T <sub>J</sub> = 25°C		с	T <sub>J</sub> = -40°C TO 125°C			
PARAMETERS	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	MAX	UNITS	
Lower Turn-Off Propagation Delay (LI Falling to LO Falling)	t <sub>LPHL</sub>		-	20	35	-	45	ns	
Upper Turn-Off Propagation Delay (HI Falling to HO Falling)	t <sub>HPHL</sub>		-	20	35	-	45	ns	
Lower Turn-On Propagation Delay (LI Rising to LO Rising)	t <sub>LPLH</sub>		-	20	35	-	45	ns	
Upper Turn-On Propagation Delay (HI Rising to HO Rising)	t <sub>HPLH</sub>		-	20	35	-	45	ns	
Delay Matching: Lower Turn-On and Upper Turn-Off	t <sub>MON</sub>		-	2	8	-	10	ns	
Delay Matching: Lower Turn-Off and Upper Turn-On	t <sub>MOFF</sub>		-	2	8	-	10	ns	
Either Output Rise/Fall Time	t <sub>RC</sub> , t <sub>FC</sub>	C <sub>L</sub> = 1000pF	-	10	-	-	-	ns	
Either Output Rise/Fall Time (3V to 9V)	t <sub>R</sub> , t <sub>F</sub>	C <sub>L</sub> = 0.1μF	-	0.5	0.6	-	0.8	us	
Either Output Rise Time Driving DMOS	t <sub>RD</sub>	C <sub>L</sub> = IRFR120	-	20	-	-	-	ns	
Either Output Fall Time Driving DMOS	t <sub>FD</sub>	C <sub>L</sub> = IRFR120	-	10	-	-	-	ns	
Minimum Input Pulse Width that Changes the Output	t <sub>PW</sub>		-	-	-	-	50	ns	
Bootstrap Diode Turn-On or Turn-Off Time	t <sub>BS</sub>		-	10	-	-	-	ns	

## **Pin Descriptions**

SYMBOL	DESCRIPTION
V <sub>DD</sub>	Positive Supply to lower gate drivers. De-couple this pin to V <sub>SS</sub> . Bootstrap diode connected to HB.
HB	High-Side Bootstrap supply. External bootstrap capacitor is required. Connect positive side of bootstrap capacitor to this pin. Bootstrap diode is on-chip.
НО	High-Side Output. Connect to gate of High-Side power MOSFET.
HS	High-Side Source connection. Connect to source of High-Side power MOSFET. Connect negative side of bootstrap capacitor to this pin.
HI	High-Side input.
LI	Low-Side input.
V <sub>SS</sub>	Chip negative supply, generally will be ground.
LO	Low-Side Output. Connect to gate of Low-Side power MOSFET.
EPAD	Exposed Pad. Connect to ground or float. The EPAD is electrically isolated from all other pins.

# Timing Diagrams

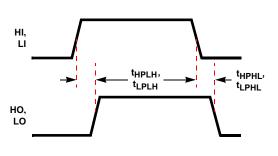
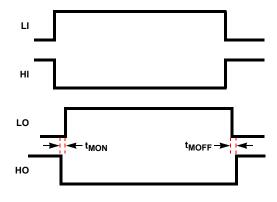
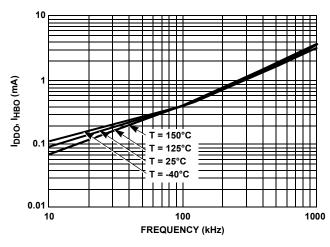
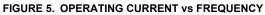


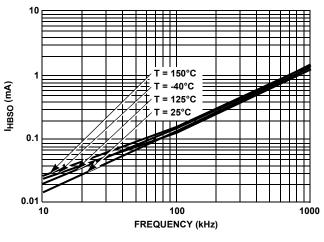
FIGURE 3.













# Typical Performance Curves



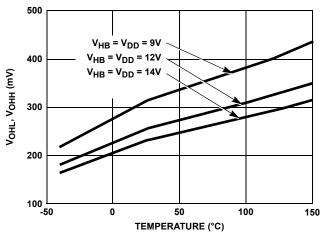


FIGURE 7. HIGH LEVEL OUTPUT VOLTAGE vs TEMPERATURE

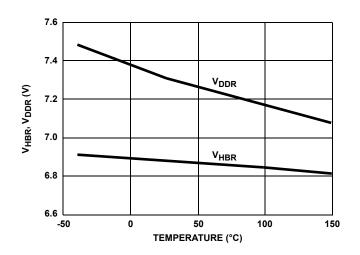


FIGURE 9. UNDERVOLTAGE LOCKOUT THRESHOLD vs TEMPERATURE

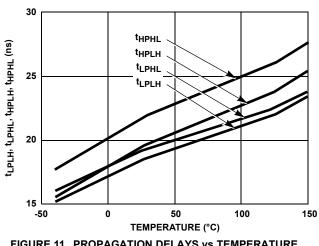


FIGURE 11. PROPAGATION DELAYS vs TEMPERATURE

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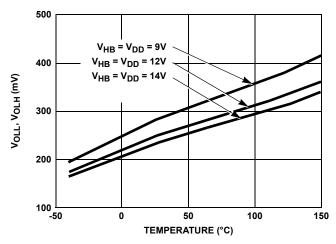
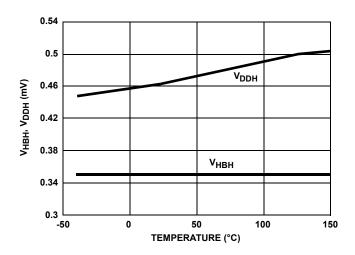
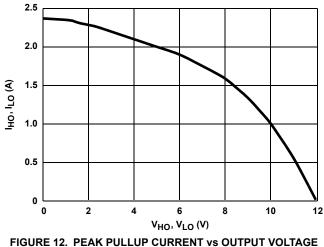


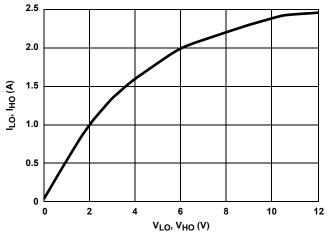
FIGURE 8. LOW LEVEL OUTPUT VOLTAGE vs TEMPERATURE

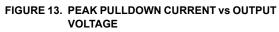


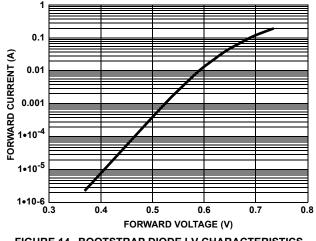














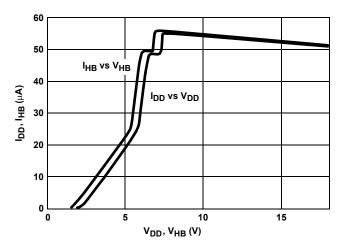


FIGURE 15. QUIESCENT CURRENT vs VOLTAGE

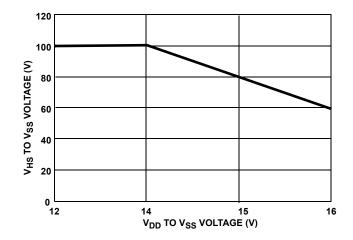
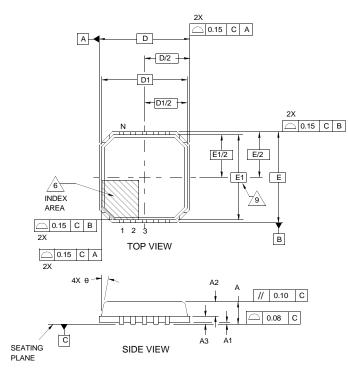
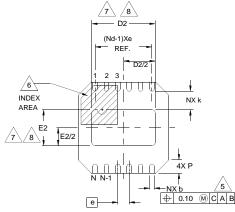


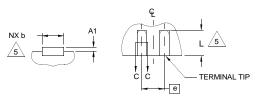
FIGURE 16. V<sub>HS</sub> VOLTAGE vs V<sub>DD</sub> VOLTAGE







BOTTOM VIEW



FOR EVEN TERMINAL/SIDE

#### L12.4x4A

### 12 LEAD DUAL FLAT NO-LEAD PLASTIC PACKAGE

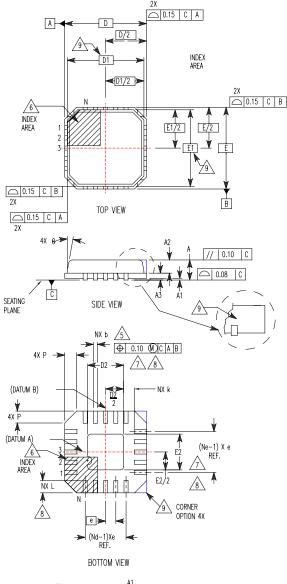
SYMBOL	MIN	NOMINAL	MAX	NOTES		
А	-	0.85	0.90	-		
A1	0.00	0.01	0.05	-		
A2	-	0.65	0.70	-		
A3		0.20 REF		-		
b	0.18	0.23	0.30	5, 8		
D		4.00 BSC		-		
D1		3.75 BSC				
D2	2.65	2.80	2.95	7, 8		
Е		4.00 BSC		-		
E1		3.75 BSC		-		
E2	1.43	1.58	1.73	7, 8		
е		0.50 BSC		-		
k	0.635	-	-	-		
L	0.30	0.40	0.50	8		
Ν		12				
Nd		6				
Р	0.24	0.42	0.60	-		
θ	-	-	12	-		

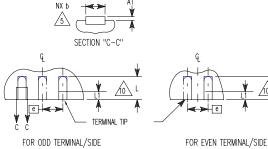
Rev. 0 8/03

NOTES:

- 1. Dimensioning and tolerancing conform to ASME Y14.5M-1994.
- 2. N is the number of terminals.
- 3. Nd refer to the number of terminals on D.
- 4. All dimensions are in millimeters. Angles are in degrees.
- 5. Dimension b applies to the metallized terminal and is measured between 0.15mm and 0.30mm from the terminal tip.
- 6. The configuration of the pin #1 identifier is optional, but must be located within the zone indicated. The pin #1 identifier may be either a mold or mark feature.
- 7. Dimensions D2 and E2 are for the exposed pads which provide improved electrical and thermal performance.
- 8. Nominal dimensions are provided to assist with PCB Land Pattern Design efforts, see Intersil Technical Brief TB389.
- 9. COMPLIANT TO JEDEC MO-229-VGGD-2 ISSUE C except for the L dimension.

### Quad Flat No-Lead Plastic Package (QFN) Micro Lead Frame Plastic Package (MLFP)





### L16.5x5

#### 16 LEAD QUAD FLAT NO-LEAD PLASTIC PACKAGE (COMPLIANT TO JEDEC MO-220VHHB ISSUE C)

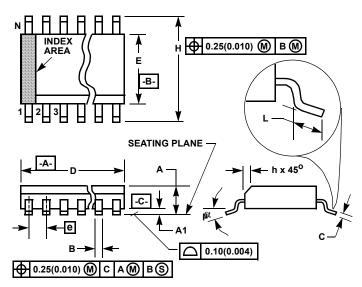
		MILLIMETERS		
SYMBOL	MIN	NOMINAL	MAX	NOTES
А	0.80	0.90	1.00	-
A1	-	-	0.05	-
A2	-	-	1.00	9
A3		0.20 REF		9
b	0.28	0.33	0.40	5, 8
D		5.00 BSC		-
D1		4.75 BSC		9
D2	2.55	2.70	2.85	7, 8
E		5.00 BSC		-
E1		4.75 BSC		9
E2	2.55	2.70	2.85	7, 8
е		0.80 BSC		-
k	0.25	-	-	-
L	0.35	0.60	0.75	8
L1	-	-	0.15	10
Ν		16		2
Nd		4		3
Ne	4	4		3
Р	-	-	0.60	9
θ	-	-	12	9
			F	Rev. 2 10/0

#### NOTES:

- 1. Dimensioning and tolerancing conform to ASME Y14.5-1994.
- 2. N is the number of terminals.
- 3. Nd and Ne refer to the number of terminals on each D and E.
- 4. All dimensions are in millimeters. Angles are in degrees.
- 5. Dimension b applies to the metallized terminal and is measured between 0.15mm and 0.30mm from the terminal tip.
- 6. The configuration of the pin #1 identifier is optional, but must be located within the zone indicated. The pin #1 identifier may be either a mold or mark feature.
- 7. Dimensions D2 and E2 are for the exposed pads which provide improved electrical and thermal performance.
- 8. Nominal dimensions are provided to assist with PCB Land Pattern Design efforts, see Intersil Technical Brief TB389.
- 9. Features and dimensions A2, A3, D1, E1, P & 0 are present when Anvil singulation method is used and not present for saw singulation.
- 10. Depending on the method of lead termination at the edge of the package, a maximum 0.15mm pull back (L1) maybe present. L minus L1 to be equal to or greater than 0.3mm.

e

# Small Outline Plastic Packages (SOIC)



#### NOTES:

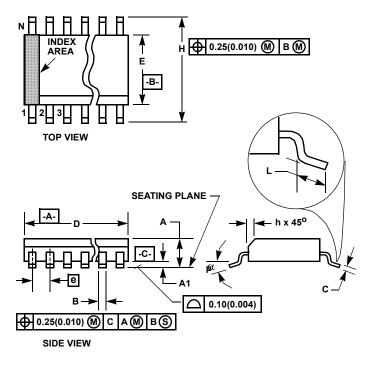
- 1. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication Number 95.
- 2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
- Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion and gate burrs shall not exceed 0.15mm (0.006 inch) per side.
- Dimension "E" does not include interlead flash or protrusions. Interlead flash and protrusions shall not exceed 0.25mm (0.010 inch) per side.
- 5. The chamfer on the body is optional. If it is not present, a visual index feature must be located within the crosshatched area.
- 6. "L" is the length of terminal for soldering to a substrate.
- 7. "N" is the number of terminal positions.
- 8. Terminal numbers are shown for reference only.
- 9. The lead width "B", as measured 0.36mm (0.014 inch) or greater above the seating plane, shall not exceed a maximum value of 0.61mm (0.024 inch).
- 10. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.

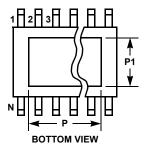
#### **M8.15** (JEDEC MS-012-AA ISSUE C) 8 LEAD NARROW BODY SMALL OUTLINE PLASTIC PACKAGE

	INC	IES	MILLIMETERS		
SYMBOL	MIN	MAX	MIN	MAX	NOTES
A	0.0532	0.0688	1.35	1.75	-
A1	0.0040	0.0098	0.10	0.25	-
В	0.013	0.020	0.33	0.51	9
С	0.0075	0.0098	0.19	0.25	-
D	0.1890	0.1968	4.80	5.00	3
E	0.1497	0.1574	3.80	4.00	4
е	0.050	0.050 BSC		BSC	-
Н	0.2284	0.2440	5.80	6.20	-
h	0.0099	0.0196	0.25	0.50	5
L	0.016	0.050	0.40	1.27	6
Ν	8	3	8		7
α	0 <sup>0</sup>	8 <sup>0</sup>	0 <sup>0</sup>	8 <sup>0</sup>	-

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## Small Outline Exposed Pad Plastic Packages (EPSOIC)





#### M8.15C

# 8 LEAD NARROW BODY SMALL OUTLINE EXPOSED PAD PLASTIC PACKAGE

	INCHES		MILLIMETERS		
SYMBOL	MIN	MAX	MIN	MAX	NOTES
A	0.056	0.066	1.43	1.68	-
A1	0.001	0.005	0.03	0.13	-
В	0.0138	0.0192	0.35	0.49	9
С	0.0075	0.0098	0.19	0.25	-
D	0.189	0.196	4.80	4.98	3
E	0.150	0.157	3.811	3.99	4
е	0.050 BSC		1.27 BSC		-
Н	0.230	0.244	5.84	6.20	-
h	0.010	0.016	0.25	0.41	5
L	0.016	0.035	0.41	0.89	6
N	8		8		7
α	0 <sup>0</sup>	8 <sup>0</sup>	0 <sup>0</sup>	8 <sup>0</sup>	-
Р	-	0.126	-	3.200	11
P1	-	0.099	-	2.514	11
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#### NOTES:

- 1. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication Number 95.
- 2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
- Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion and gate burrs shall not exceed 0.15mm (0.006 inch) per side.
- Dimension "E" does not include interlead flash or protrusions. Interlead flash and protrusions shall not exceed 0.25mm (0.010 inch) per side.
- 5. The chamfer on the body is optional. If it is not present, a visual index feature must be located within the crosshatched area.
- 6. "L" is the length of terminal for soldering to a substrate.
- 7. "N" is the number of terminal positions.
- 8. Terminal numbers are shown for reference only.
- 9. The lead width "B", as measured 0.36mm (0.014 inch) or greater above the seating plane, shall not exceed a maximum value of 0.61mm (0.024 inch).
- 10. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.
- Dimensions "P" and "P1" are thermal and/or electrical enhanced variations. Values shown are maximum size of exposed pad within lead count and body size.

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